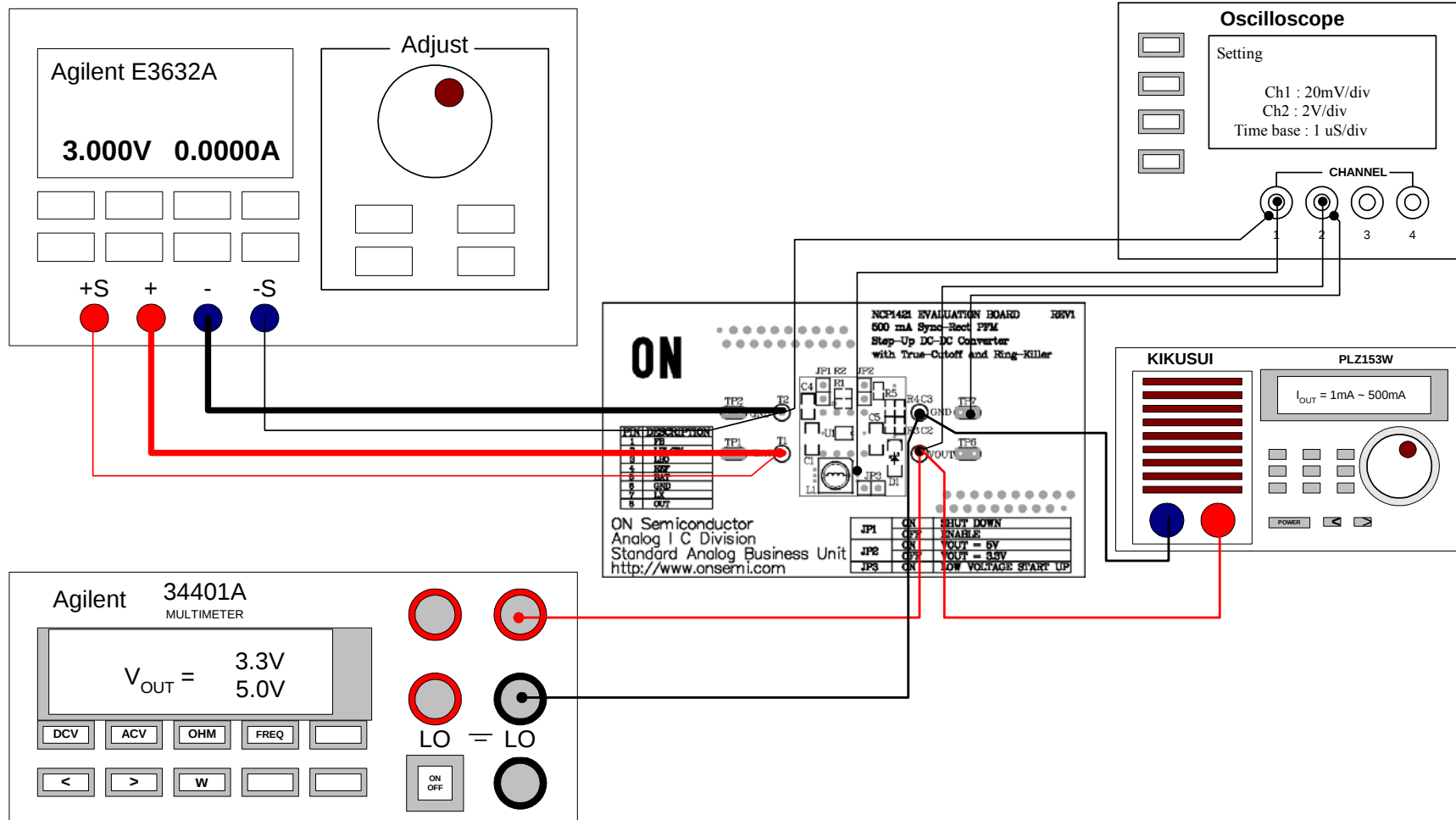


Test Procedure for the NCP1421

ON Semiconductor



01/01/2004



Test Procedure:

1. Connect the test setup as shown above.
2. **Turn OFF the JP1**; (Enable the device).
3. Set the Power Supply to 3.0V and apply to TP1, TP2 (T1, T2).
4. Apply 500mA loading from the electronic load.
5. Check the input current (I_{IN}), output voltage (V_{OUT}) and output ripple;
 - For $V_{OUT} = 3.3V$; **JP2 OFF**
 $I_{IN} = 590.7mA \sim 608.7mA$
 $V_{OUT} = 3.267 \sim 3.367V$
 $V_{RIPPLE} \leq 35mV$
 - For $V_{OUT} = 5V$; **JP2 ON**
 $I_{IN} = 931.07mA \sim 957.4mA$
 $V_{OUT} = 4.859 \sim 5.0075V$
 $V_{RIPPLE} \leq 40mV$
6. Check the switching waveform at scope CH1 to see whether it is a normal continuous conduction mode switching node waveform and switching ON time (T_{ON}) is between $0.46\mu s \sim 1.15\mu s$.